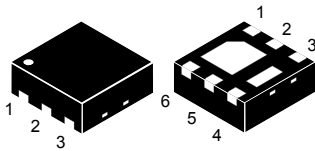
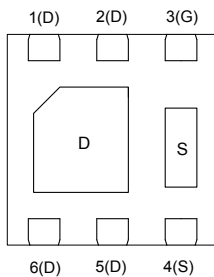


## P-channel 30 V, 48 mΩ typ., 4 A, STripFET H6 Power MOSFET in a PowerFLAT 2x2 package


**PowerFLAT 2x2**


Bottom view

AM11269v1


**Product status link**
[STL4P3LLH6](#)
**Product summary**

<b>Order code</b>	STL4P3LLH6
<b>Marking</b>	4K3L
<b>Package</b>	PowerFLAT 2x2
<b>Packing</b>	Tape and reel

### Features

Order code	$V_{DS}$	$R_{DS(on)}$ max.	$I_D$
STL4P3LLH6	30 V	56 mΩ	4 A

- Very low on-resistance
- Very low gate charge
- High avalanche ruggedness
- Low gate drive power loss

### Applications

- Switching applications

### Description

This device is a P-channel Power MOSFET developed using the STripFET H6 technology with a new trench gate structure. The resulting Power MOSFET exhibits very low  $R_{DS(on)}$  in all packages.

# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	30	V
$V_{GS}$	Gate-source voltage	$\pm 20$	V
$I_D$	Drain current (continuous) at $T_A = 25\text{ }^\circ\text{C}$	4	A
	Drain current (continuous) at $T_A = 100\text{ }^\circ\text{C}$	2.75	
$I_{DM}^{(1)}$	Drain current (pulsed)	16	A
$P_{TOT}$	Total power dissipation at $T_A = 25\text{ }^\circ\text{C}$	2.4	W
$T_{stg}$	Storage temperature range	-55 to 150	$^\circ\text{C}$
$T_J$	Operating junction temperature		

1. Pulse width limited by safe operating area.

**Table 2. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thJA}^{(1)}$	Thermal resistance, junction-to-ambient	52	$^\circ\text{C/W}$

1. When mounted on 1 inch<sup>2</sup> FR-4, 2 Oz copper board.

**Note:** For the P-channel Power MOSFET the actual polarity of the voltages and the current must be reversed.

## 2 Electrical characteristics

( $T_C = 25\text{ }^\circ\text{C}$  unless otherwise specified)

**Table 3. On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}$ , $I_D = 250\text{ }\mu\text{A}$	30			V
$I_{DSS}$	Zero gate voltage drain current	$V_{GS} = 0\text{ V}$ , $V_{DS} = 30\text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0\text{ V}$ , $V_{DS} = 30\text{ V}$ , $T_C = 125\text{ }^\circ\text{C}^{(1)}$			10	
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0\text{ V}$ , $V_{GS} = \pm 20\text{ V}$			100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250\text{ }\mu\text{A}$	1.0		2.5	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$ , $I_D = 2\text{ A}$		48	56	m $\Omega$
		$V_{GS} = 4.5\text{ V}$ , $I_D = 2\text{ A}$		75	90	

1. Defined by design, not subject to production test.

**Table 4. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$ , $V_{GS} = 0\text{ V}$	-	639	-	pF
$C_{oss}$	Output capacitance		-	79	-	pF
$C_{rSS}$	Reverse transfer capacitance		-	52	-	pF
$Q_g$	Total gate charge	$V_{DD} = 15\text{ V}$ , $I_D = 4\text{ A}$ , $V_{GS} = 4.5\text{ V}$ (see Figure 13. Gate charge test circuit)	-	6	-	nC
$Q_{gs}$	Gate-source charge		-	1.9	-	nC
$Q_{gd}$	Gate-drain charge		-	2.1	-	nC

**Table 5. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 15\text{ V}$ , $I_D = 4\text{ A}$ , $R_G = 4.7\text{ }\Omega$ , $V_{GS} = 10\text{ V}$ (see Figure 12. Switching times test circuit for resistive load)	-	5.4	-	ns
$t_r$	Rise time		-	5	-	ns
$t_{d(off)}$	Turn-off delay time		-	19.2	-	ns
$t_f$	Fall time		-	3.4	-	ns

**Table 6. Source-drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{SD}^{(1)}$	Forward on voltage	$I_{SD} = 4\text{ A}$ , $V_{GS} = 0\text{ V}$	-		1.1	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 4\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ , $V_{DD} = 16\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$ (see Figure 14. Test circuit for inductive load switching and diode recovery times)	-	11.2		ns
$Q_{rr}$	Reverse recovery charge		-	3.5		nC
$I_{RRM}$	Reverse recovery current		-	0.6		A

1. Pulsed: Pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

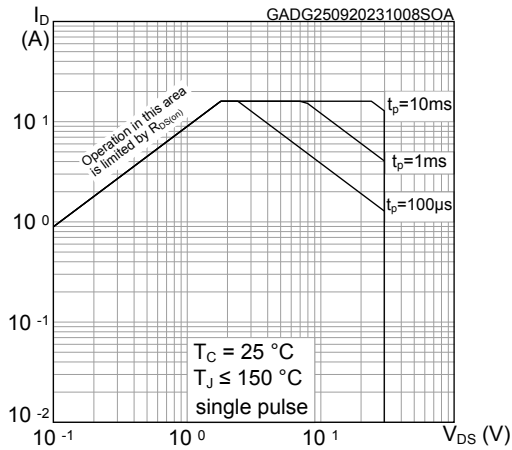


Figure 2. Normalized transient thermal impedance

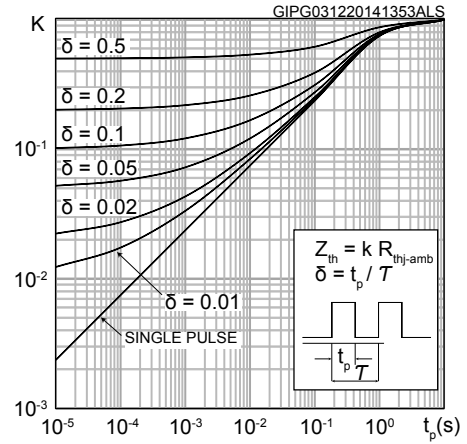


Figure 3. Typical output characteristics

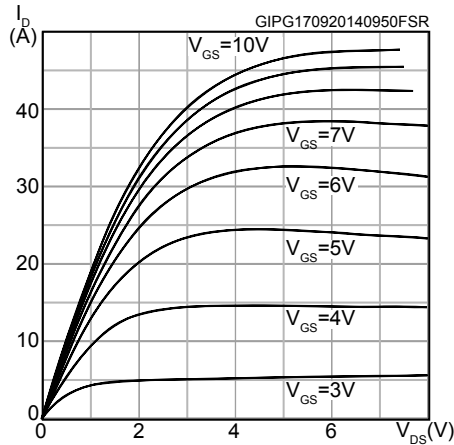


Figure 4. Typical transfer characteristics

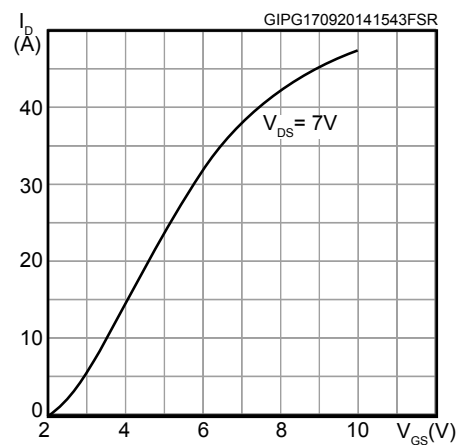


Figure 5. Typical gate charge vs gate-source voltage

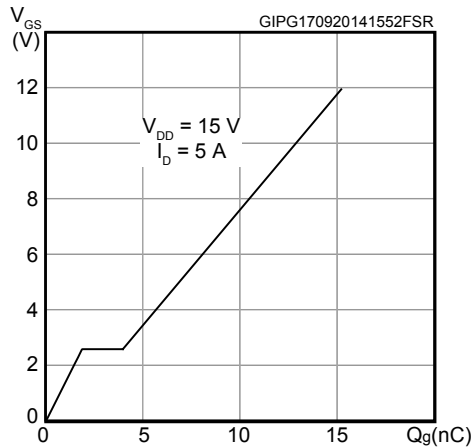


Figure 6. Typical static drain-source on-resistance

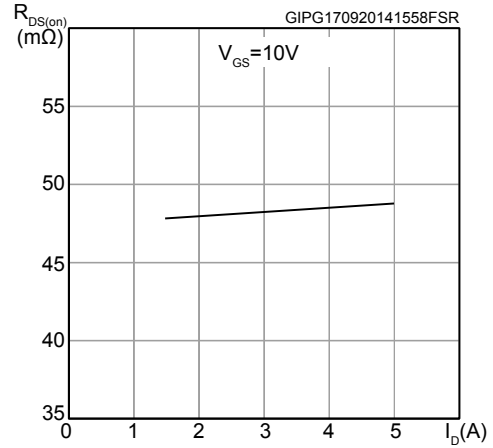


Figure 7. Normalized breakdown voltage vs temperature

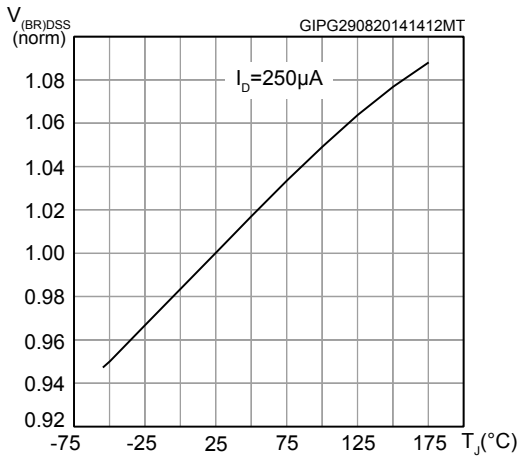


Figure 8. Typical capacitance characteristics

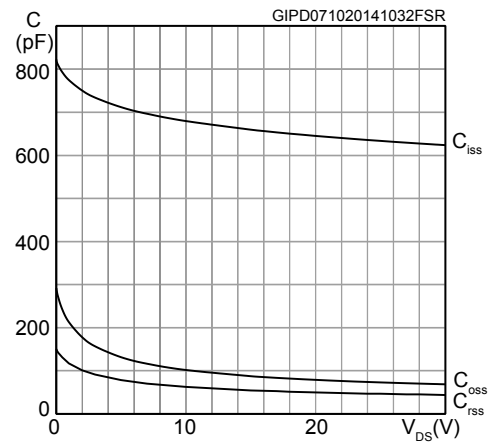


Figure 9. Normalized gate threshold voltage vs temperature

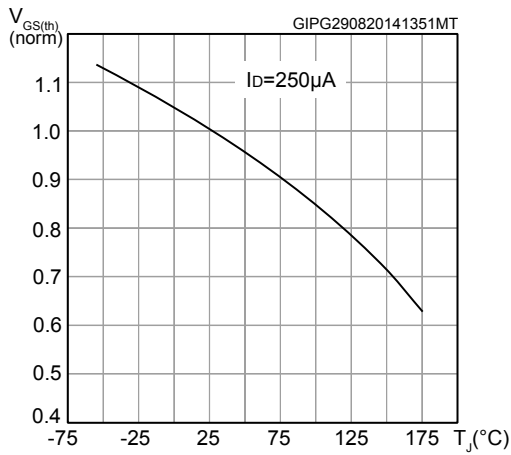


Figure 10. Normalized on-resistance vs temperature

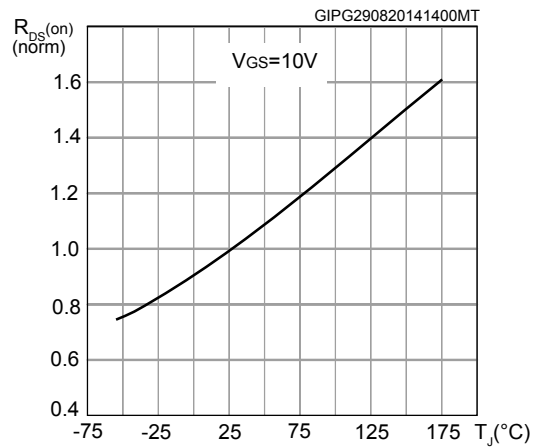
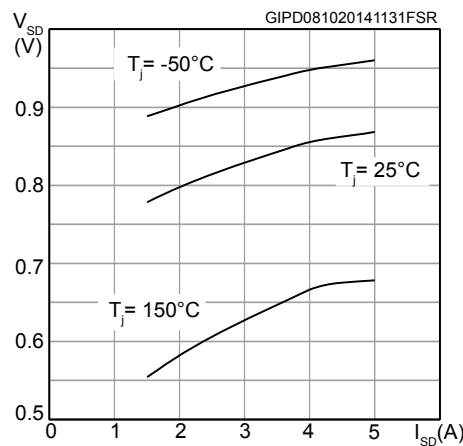
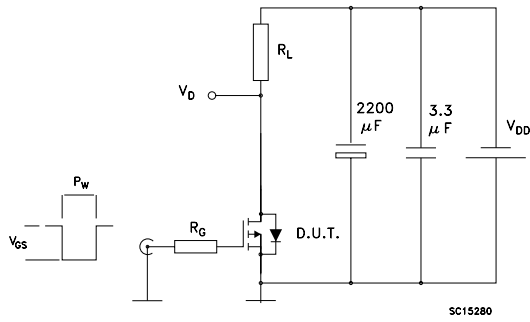
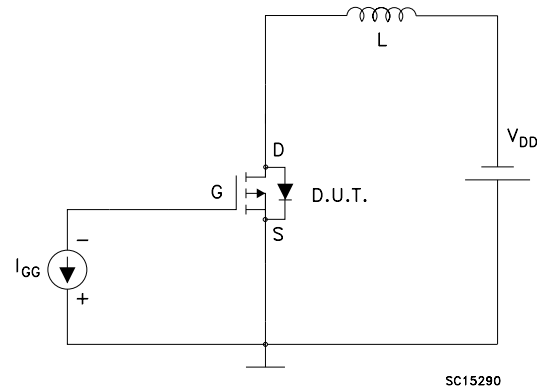
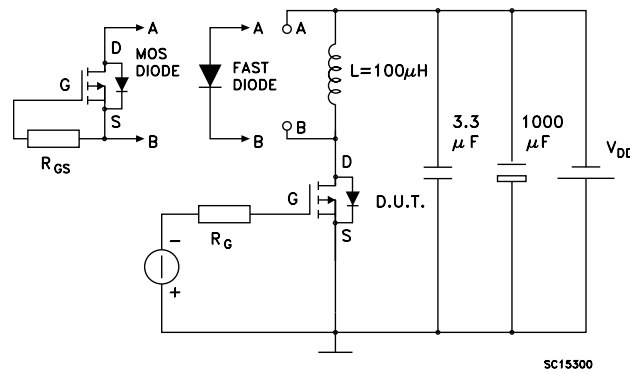


Figure 11. Typical reverse diode forward characteristics



Note: For the P-channel Power MOSFET, current and voltage polarities are reversed.

### 3 Test circuits

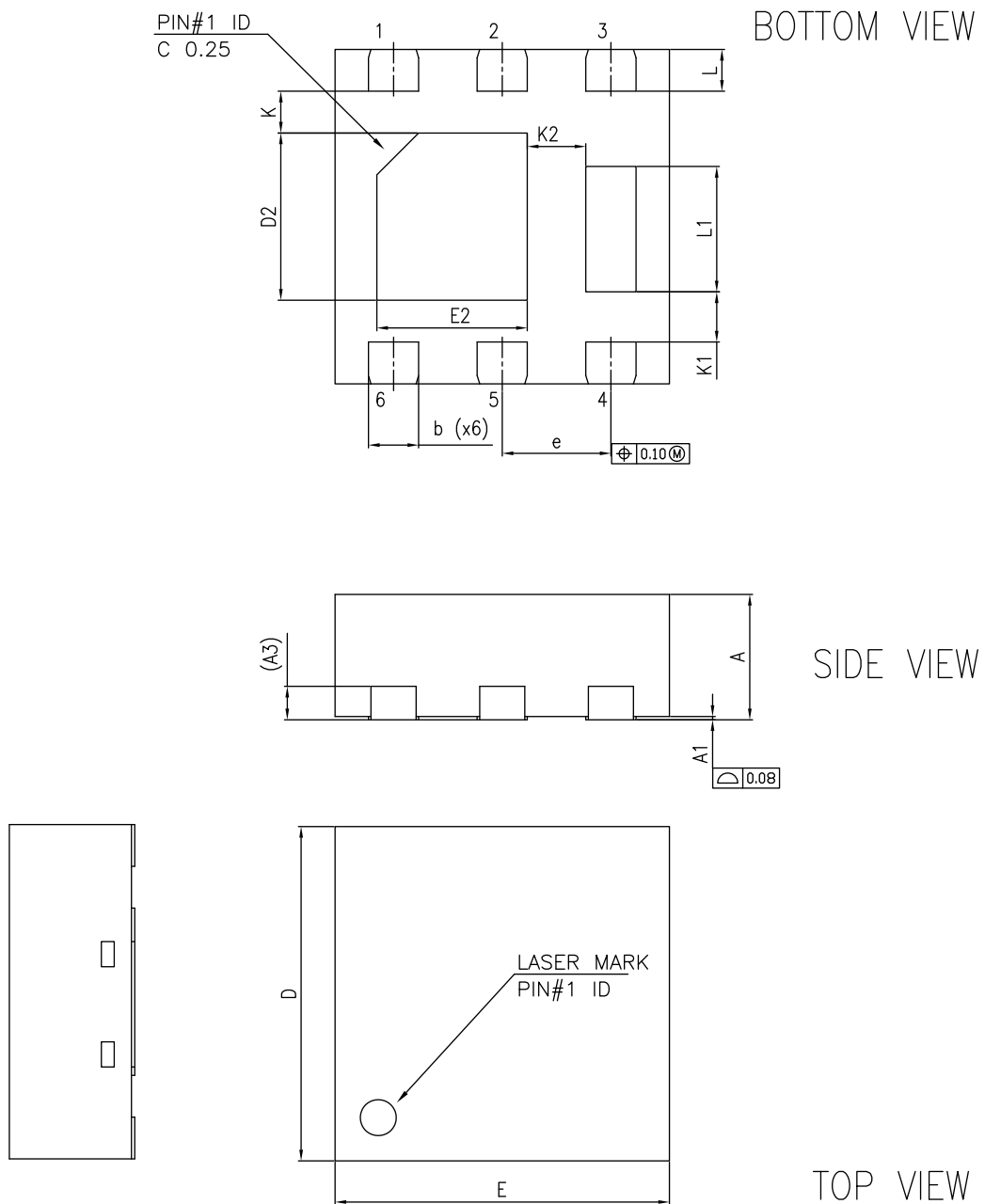
**Figure 12. Switching times test circuit for resistive load**

**Figure 13. Gate charge test circuit**

**Figure 14. Test circuit for inductive load switching and diode recovery times**


## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 PowerFLAT 2x2 package information

Figure 15. PowerFLAT 2x2 package outline







## Revision history

**Table 8. Document revision history**

Date	Version	Changes
09-May-2013	1	Initial revision.
09-Dec-2014	2	Text edits throughout document On cover page: – changed title description – updated features and description In Table 4, changed $R_{DS(on)}$ values In Table 5, changed values and test conditions In Table 6, changed values and test conditions In Table 7, changed values and test conditions Added Section 2.1: Electrical characteristics (curves) Updated Section 3: Test circuits Updated Section 4: Package mechanical data
27-Sep-2023	3	Updated <a href="#">Figure 1. Safe operating area.</a> Updated <a href="#">Section 4 Package information.</a> Minor text changes.

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<b>3</b>	<b>Test circuits</b> .....	<b>6</b>
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